

Direct observations of the mechanism of nickel suicide formation on Si(100) and Si 0.75Ge 0.25 substrates

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Electrochemical and Solid-State Letters

2004; 7(10):G231-G234

ARTICLE IDENTIFIERS

DOI: 10.1149/1.1789851

PMID: unavailable

PMCID: not available

JOURNAL IDENTIFIERS

LCCN: not available

pISSN: 1099-0062

eISSN: not available

OCLC ID: not available

CONS ID: not available

US National Library of Medicine ID: not available

This article was identified from a query of the SafetyLit database.